



LIST OF REFERENCES CITED BY APPLICANT <i>(Use several sheets if necessary)</i>					ATTY. DOCKET NO.:	APPLICATION NO.:	
					4717-13000	10/827,437	
					APPLICANT:		
					Takeshi AKATSU		
FILING DATE: April 20, 2004					GROUP:	1765	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	6,524,935 B1	2/2003	Canaperi et al.	438	478	
	AB						
	AC						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES
	AD	EP 1 258 544 A1	11/2002	Europe			<input checked="" type="checkbox"/> X
	AE	WO 03/009366 A1	1/2003	PCT			<input checked="" type="checkbox"/> X
	AF						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
	AG	L. Huang et al., XP001116664 "Electron And Hole Mobility Enhancement In Strained SOI By Wafer Bonding", IEEE Transactions On Electron Devices, Vol. 49, No. 9, pp. 1566-1567 (2002).					
	AH	L. Huang et al., XP001020601, "Sige-On-Insulator Prepared By Wafer Bonding And Layer Transfer For High-Performance Field-Effect Transistor", Applied Physics Letters, American Institute Of Physics, Vol. 78, No. 9, pp 1267-1269, (2001).					
	AI	C. Maleville et al., XP-001003462, "Multiple SOI Layers By Multiple Smart-Cut Transfers", 2000 IEEE International SOI Conference, pp. 134-135, (2000).					
	AJ						
	AK						
EXAMINER				DATE CONSIDERED			
				<i>3/31/08</i>			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

LIST OF REFERENCES CITED BY APPLICANT <i>(Use several sheets if necessary)</i>					ATTY. DOCKET NO.:	APPLICATION NO.:		
					4717-13000	Not yet assigned		
					APPLICANT:			
					Takeshi AKATSU <i>et al.</i>	FILING DATE:	GROUP:	
Filed concurrently herewith								

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>AA</i>	AA	6,039,803	3/2000	Fitzgerald et al.	117	89	
<i>AB</i>	AB	6,464,780 B1	10/2002	Mantl et al.	117	90	
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AK							
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

AQ	
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AS	
AT	

EXAMINER	DATE CONSIDERED
<i>3/31/00</i>	

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.